

Description

The 25P06 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. This device is well suited for high current load applications.

General Features

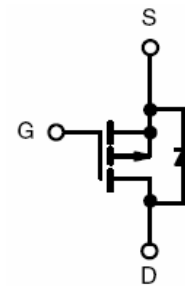
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| V_{DSS} | $R_{DS(ON)}$ @ -4.5V(typ) | I_D |
|-----------|------------------------------|-------|
| -60V | 39mΩ | -25A |

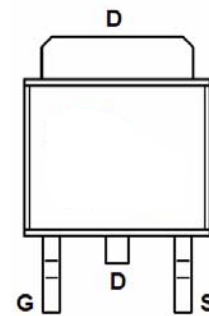
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

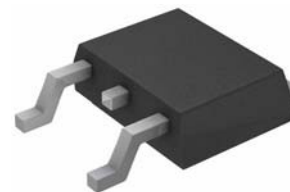
- High side switch for full bridge converter
- DC/DC converter for LCD display



Schematic diagram



Marking and pin assignment



To-252

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

| Parameter | Symbol | Limit | Unit |
|---|--------------------------|------------|---------------------|
| Drain-Source Voltage | V_{DS} | -60 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Drain Current-Continuous | I_D | -25 | A |
| Drain Current-Continuous($T_C=100^\circ\text{C}$) | $I_D(100^\circ\text{C})$ | -17.7 | A |
| Pulsed Drain Current | I_{DM} | -60 | A |
| Maximum Power Dissipation | P_D | 90 | W |
| Derating factor | | 0.72 | W/ $^\circ\text{C}$ |
| Single pulse avalanche energy ^(Note 5) | E_{AS} | 300 | mJ |
| Operating Junction and Storage Temperature Range | T_J, T_{STG} | -55 To 150 | $^\circ\text{C}$ |

Thermal Characteristic

| | | | |
|--|-----------------|-----|---------------|
| Thermal Resistance, Junction-to-Case ^(Note 2) | $R_{\theta JC}$ | 1.4 | $^{\circ}C/W$ |
|--|-----------------|-----|---------------|

Electrical Characteristics ($T_C=25^{\circ}C$ unless otherwise noted)

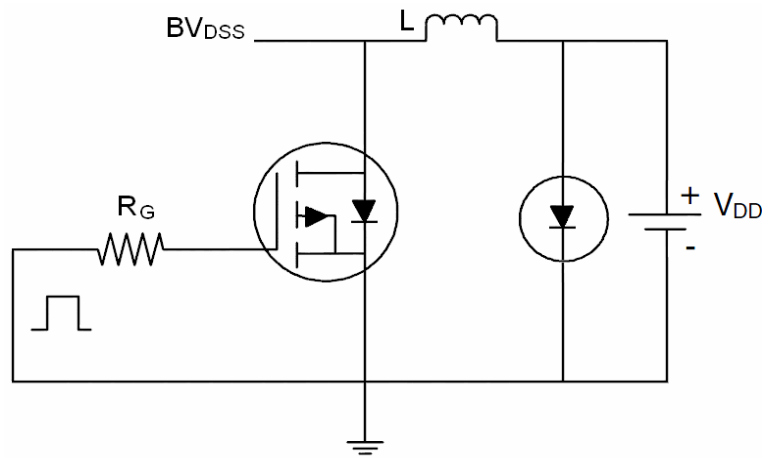
| Parameter | Symbol | Condition | Min | Typ | Max | Unit |
|--|--------------|--|-----|------|-----------|------------|
| Off Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{GS}=0V, I_D=-250\mu A$ | -60 | - | - | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS}=-60V, V_{GS}=0V$ | - | - | -1 | μA |
| Gate-Body Leakage Current | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | - | - | ± 100 | nA |
| On Characteristics ^(Note 3) | | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}, I_D=-250\mu A$ | -2 | -2.9 | -3.5 | V |
| Drain-Source On-State Resistance | $R_{DS(ON)}$ | $V_{GS}=-10V, I_D=-20A$ | - | 39 | 45 | m Ω |
| Forward Transconductance | g_{FS} | $V_{DS}=-10V, I_D=-10A$ | - | 25 | - | S |
| Dynamic Characteristics ^(Note 4) | | | | | | |
| Input Capacitance | C_{iss} | $V_{DS}=-30V, V_{GS}=0V,$ $F=1.0MHz$ | - | 3430 | - | PF |
| Output Capacitance | C_{oss} | | - | 391 | - | PF |
| Reverse Transfer Capacitance | C_{rss} | | - | 272 | - | PF |
| Switching Characteristics ^(Note 4) | | | | | | |
| Turn-on Delay Time | $t_{d(on)}$ | $V_{DD}=-30V, R_L=1.5\Omega,$ $V_{GS}=-10V, R_G=3\Omega$ | - | 12 | - | nS |
| Turn-on Rise Time | t_r | | - | 15 | - | nS |
| Turn-Off Delay Time | $t_{d(off)}$ | | - | 38 | - | nS |
| Turn-Off Fall Time | t_f | | - | 15 | - | nS |
| Total Gate Charge | Q_g | $V_{DS}=-30, I_D=-20A,$ $V_{GS}=-10V$ | - | 46 | - | nC |
| Gate-Source Charge | Q_{gs} | | - | 9.5 | - | nC |
| Gate-Drain Charge | Q_{gd} | | - | 10.5 | - | nC |
| Drain-Source Diode Characteristics | | | | | | |
| Diode Forward Voltage ^(Note 3) | V_{SD} | $V_{GS}=0V, I_S=-10A$ | - | - | -1.2 | V |
| Diode Forward Current ^(Note 2) | I_S | | - | - | -25 | A |
| Reverse Recovery Time | t_{rr} | $T_J = 25^{\circ}C, I_F = -10A$ | - | 47 | - | nS |
| Reverse Recovery Charge | Q_{rr} | $di/dt = -100A/\mu s$ (Note3) | - | 53 | - | nC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD) | | | | |

Notes:

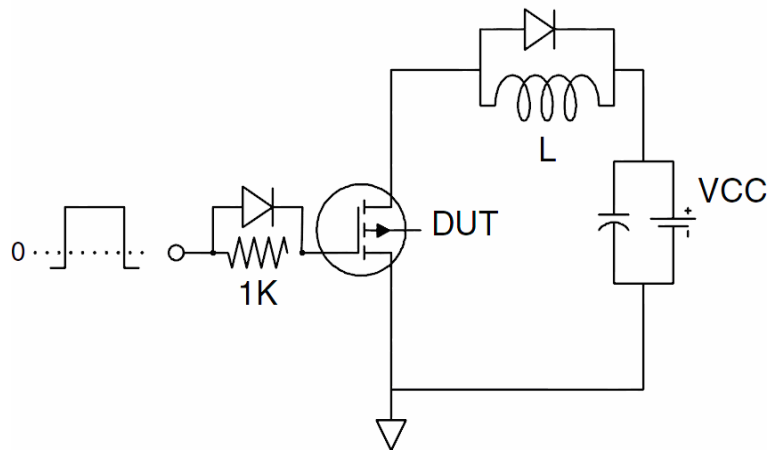
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. E_{AS} condition: $T_J=25^{\circ}C, V_{DD}=-20V, V_G=-10V, L=1mH, R_g=25\Omega, I_{AS}=33A$

Test Circuit

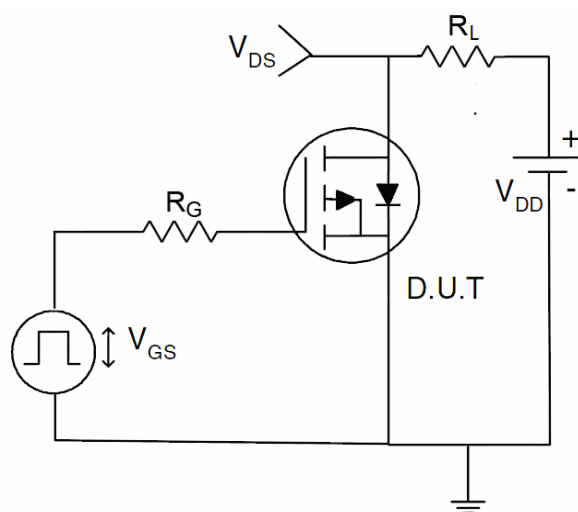
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

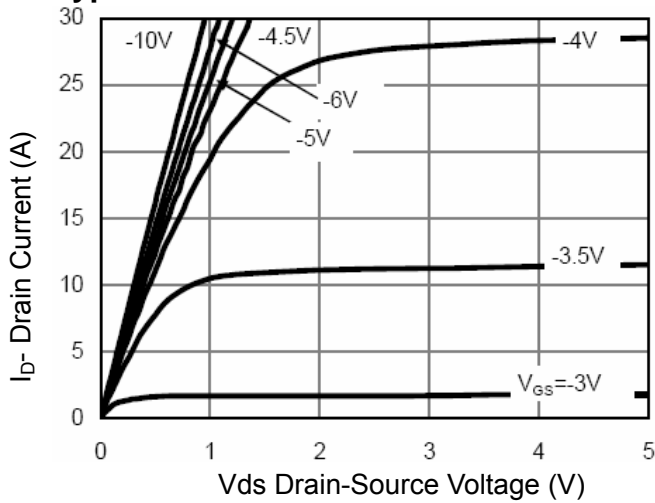


Figure 1 Output Characteristics

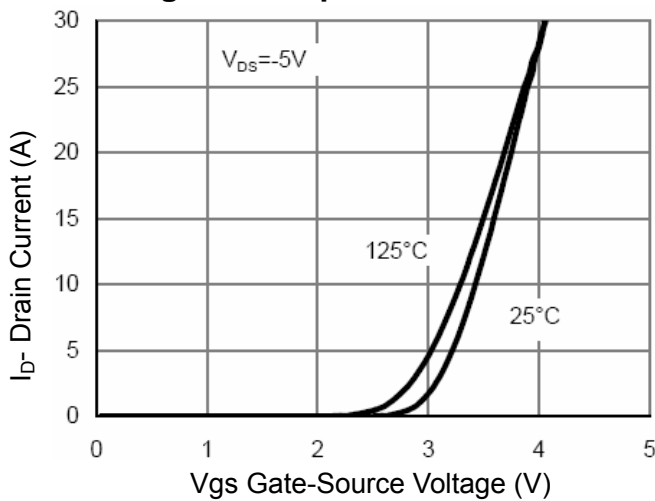


Figure 2 Transfer Characteristics

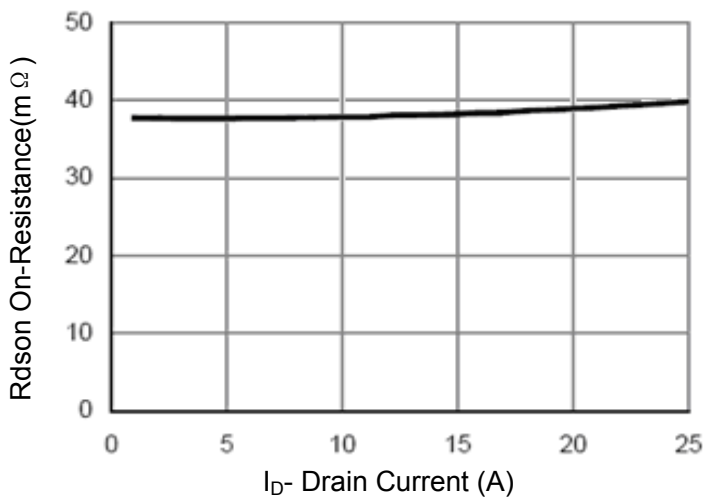


Figure 3 Rdson- Drain Current

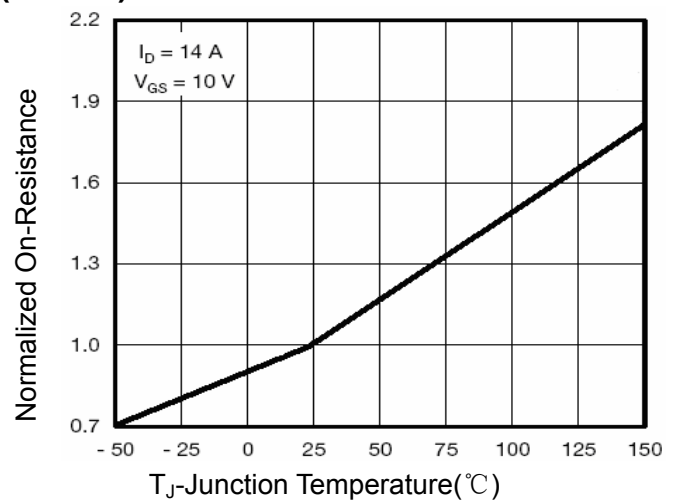


Figure 4 Rdson-Junction Temperature

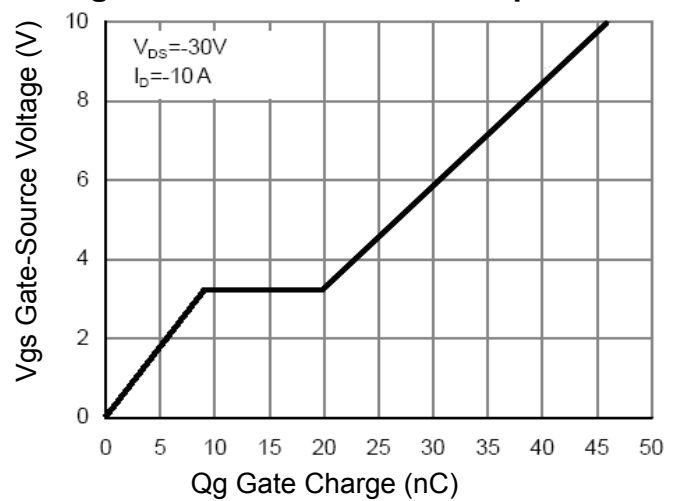


Figure 5 Gate Charge

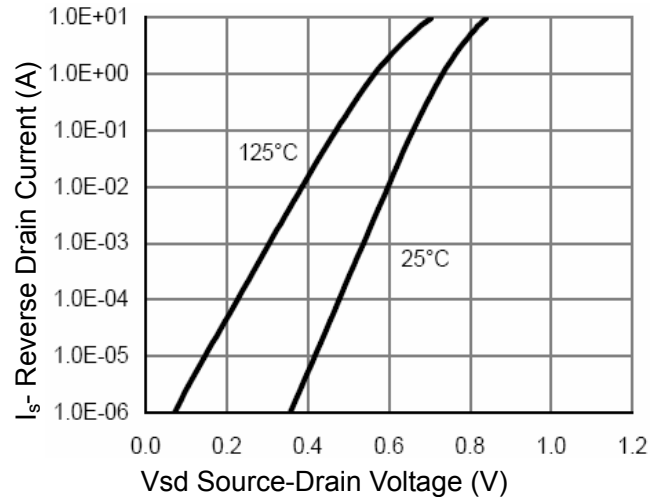


Figure 6 Source- Drain Diode Forward

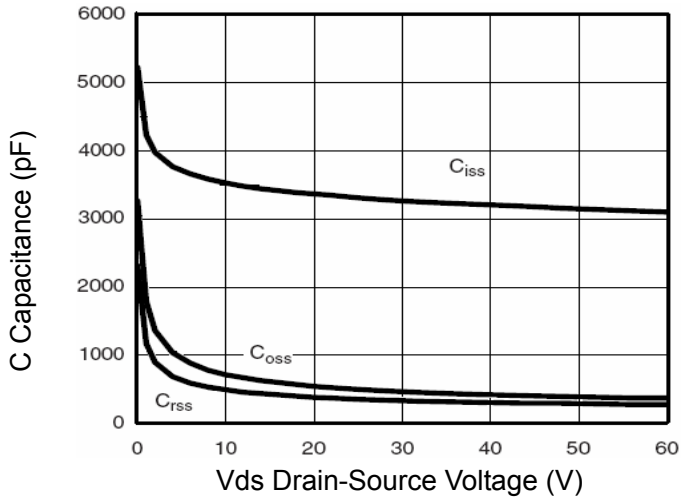


Figure 7 Capacitance vs Vds

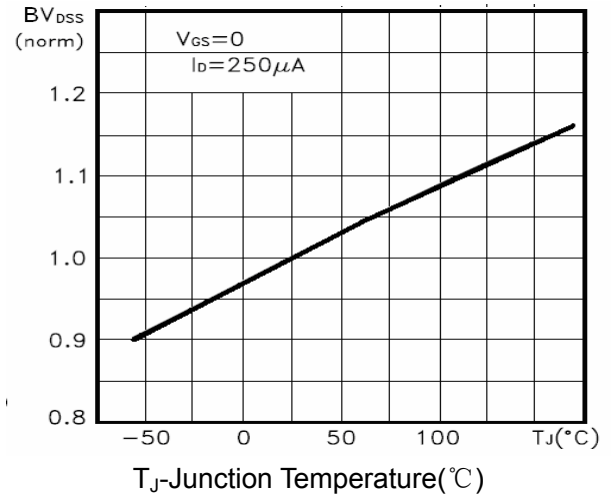


Figure 9 BV_{DSS} vs Junction Temperature

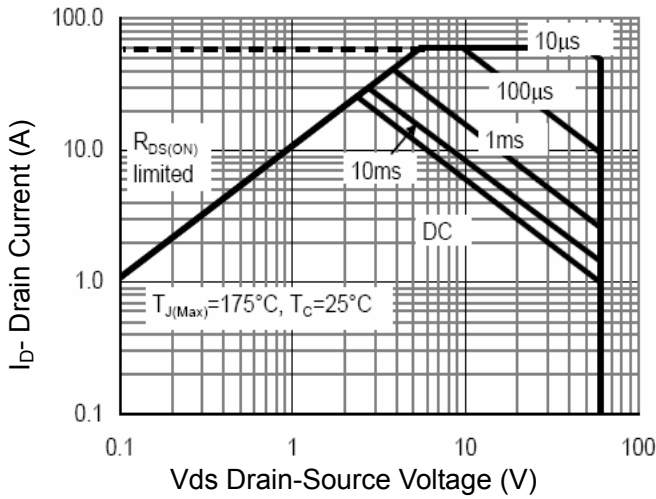


Figure 8 Safe Operation Area

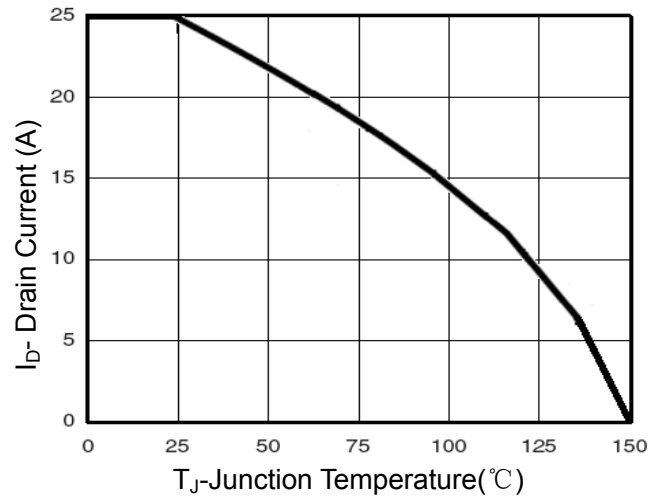


Figure 10 I_D Current De-rating

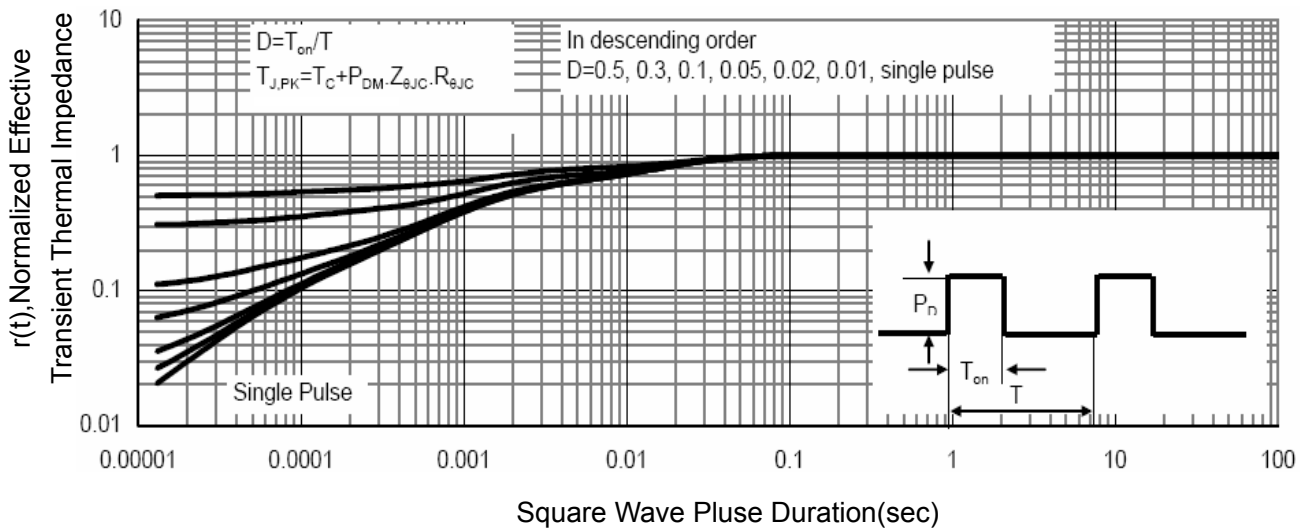


Figure 11 Normalized Maximum Transient Thermal Impedance